

74HC595-Q100; 74HCT595-Q100

8-bit serial-in, serial or parallel-out shift register with output latches; 3-state

Rev. 1 — 2 August 2012

Product data sheet

1. General description

The 74HC595-Q100; 74HCT595-Q100 are high-speed Si-gate CMOS devices and are pin compatible with Low-power Schottky TTL (LSTTL). They are specified in compliance with JEDEC standard No. 7A.

The 74HC595-Q100; 74HCT595-Q100 are 8-stage serial shift registers with a storage register and 3-state outputs. The registers have separate clocks. Data is shifted on the positive-going transitions of the shift register clock input (SHCP). The data in each register is transferred to the storage register on a positive-going transition of the storage register clock input (STCP). If both clocks are connected together, the shift register is always one clock pulse ahead of the storage register.

The shift register has a serial input (DS) and a serial standard output (Q7S) for cascading. It is also provided with asynchronous reset (active LOW) for all 8 shift register stages. The storage register has 8 parallel 3-state bus driver outputs. Data in the storage register appears at the output whenever the output enable input (\overline{OE}) is LOW.

This product has been qualified to the Automotive Electronics Council (AEC) standard Q100 (Grade 1) and is suitable for use in automotive applications.

2. Features and benefits

- Automotive product qualification in accordance with AEC-Q100 (Grade 1)
 - ◆ Specified from $-40\text{ }^{\circ}\text{C}$ to $+85\text{ }^{\circ}\text{C}$ and from $-40\text{ }^{\circ}\text{C}$ to $+125\text{ }^{\circ}\text{C}$
- 8-bit serial input
- 8-bit serial or parallel output
- Storage register with 3-state outputs
- Shift register with direct clear
- 100 MHz (typical) shift out frequency
- ESD protection:
 - ◆ MIL-STD-883, method 3015 exceeds 2000 V
 - ◆ HBM JESD22-A114F exceeds 2000 V
 - ◆ MM JESD22-A115-A exceeds 200 V (C = 200 pF, R = 0 Ω)
- Multiple package options

3. Applications

- Serial-to-parallel data conversion
- Remote control holding register



4. Ordering information

Table 1. Ordering information

Type number	Package			Version
	Temperature range	Name	Description	
74HC595D-Q100 74HCT595D-Q100	-40 °C to +125 °C	SO16	plastic small outline package; 16 leads; body width 3.9 mm	SOT109-1
74HC595PW-Q100 74HCT595PW-Q100	-40 °C to +125 °C	TSSOP16	plastic thin shrink small outline package; 16 leads; body width 4.4 mm	SOT403-1
74HC595BQ-Q100 74HCT595BQ-Q100	-40 °C to +125 °C	DHVQFN16	plastic dual in-line compatible thermal enhanced very thin quad flat package; no leads; 16 terminals; body 2.5 × 3.5 × 0.85 mm	SOT763-1

5. Functional diagram

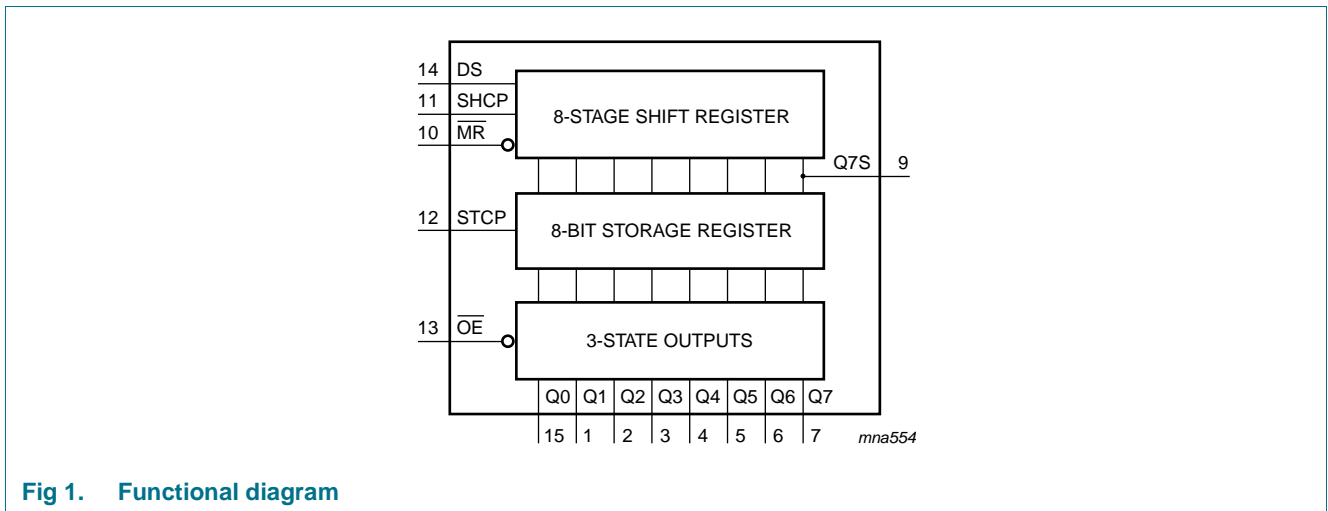


Fig 1. Functional diagram

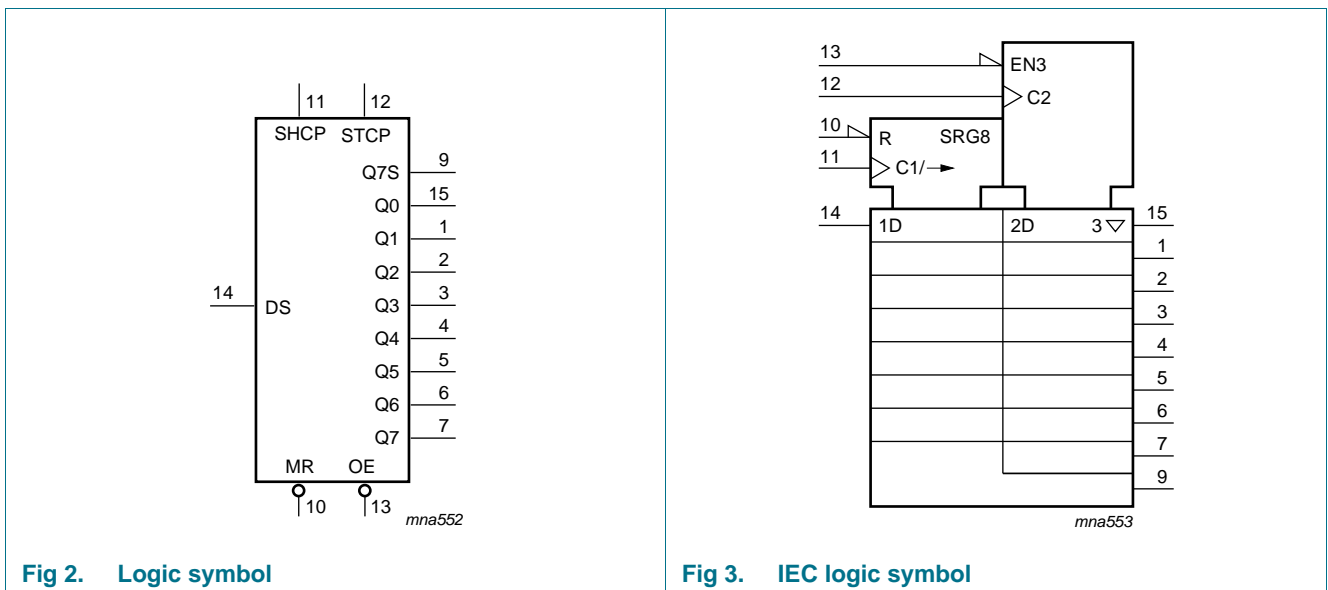
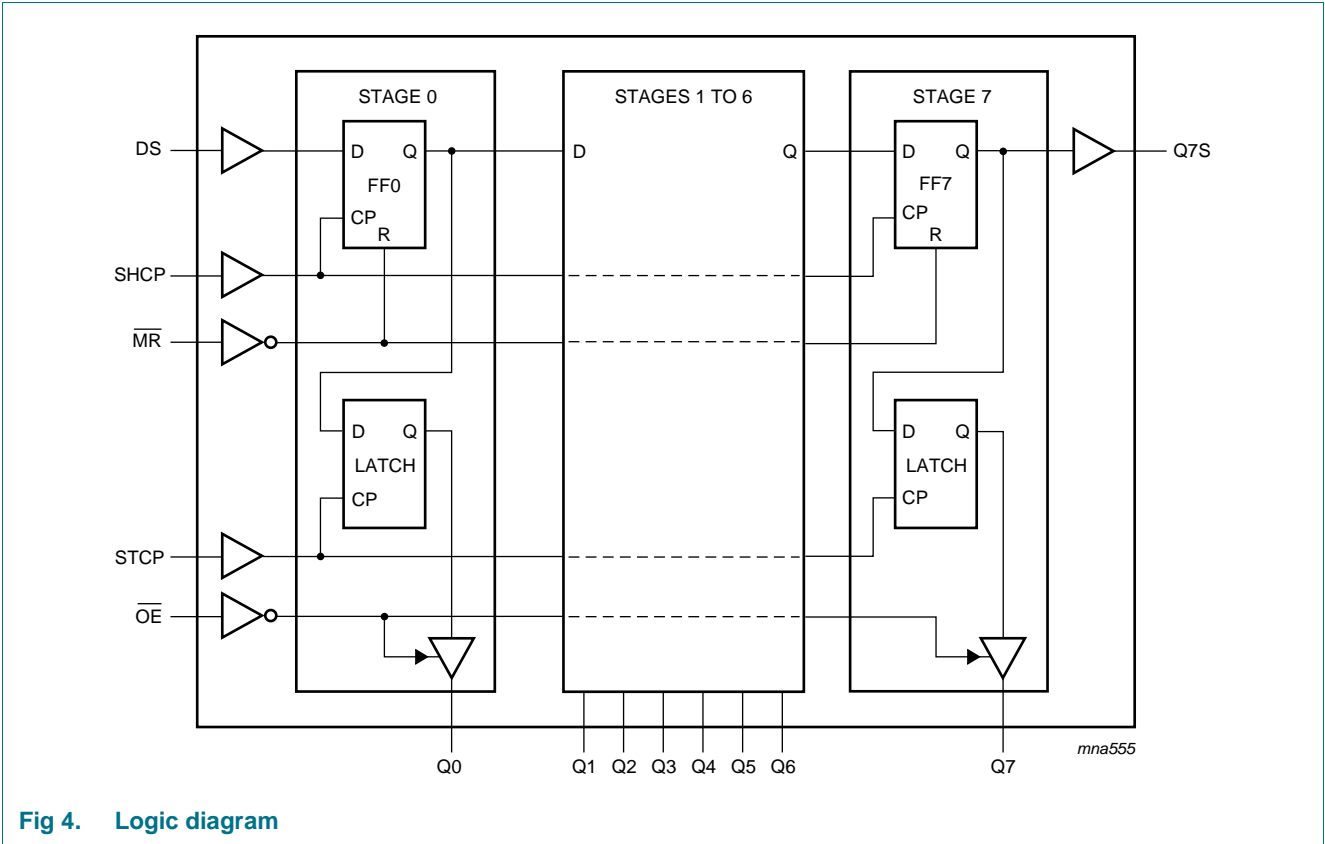


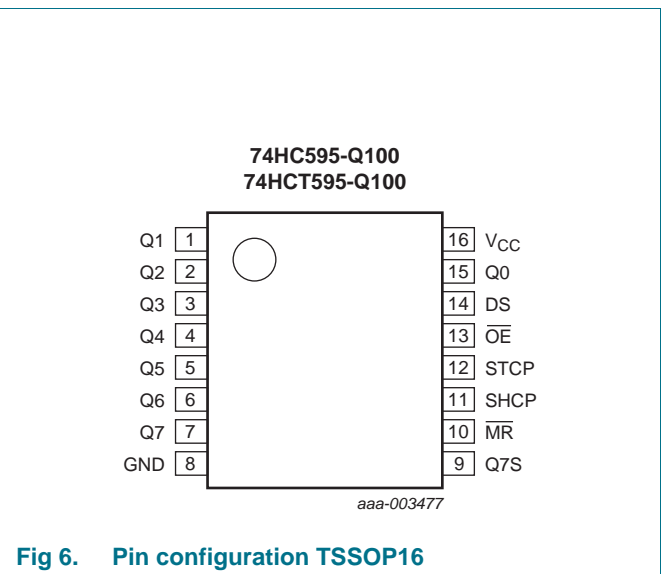
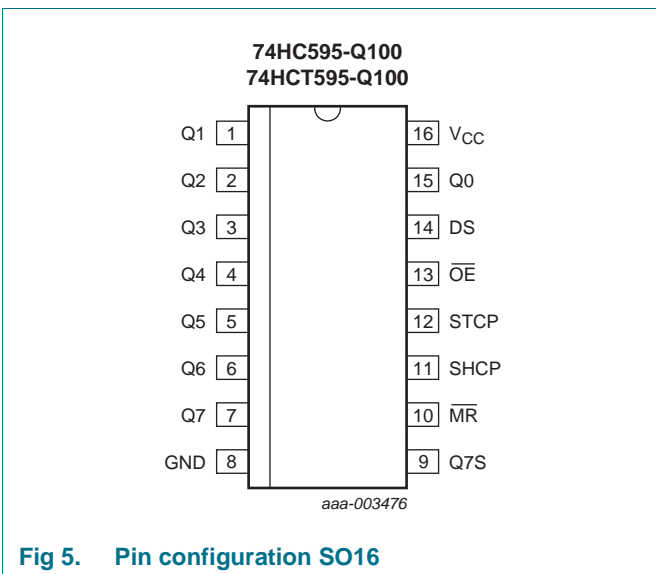
Fig 2. Logic symbol

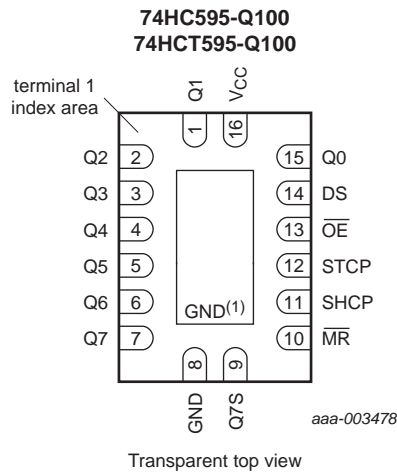
Fig 3. IEC logic symbol



6. Pinning information

6.1 Pinning





- (1) This is not a supply pin. The substrate is attached to this pad using conductive die attach material. There is no electrical or mechanical requirement to solder this pad. However, if it is soldered, the solder land should remain floating or be connected to GND.

Fig 7. Pin configuration for DHVQFN16

6.2 Pin description

Table 2. Pin description

Symbol	Pin	Description
Q0, Q1, Q2, Q3, Q4, Q5, Q6, Q7	15, 1, 2, 3, 4, 5, 6, 7	parallel data output
GND	8	ground (0 V)
Q7S	9	serial data output
MR	10	master reset (active LOW)
SHCP	11	shift register clock input
STCP	12	storage register clock input
OE	13	output enable input (active LOW)
DS	14	serial data input
V _{CC}	16	supply voltage

7. Functional description

Table 3. Function table^[1]

Control				Input	Output		Function
SHCP	STCP	\overline{OE}	\overline{MR}	DS	Q7S	Qn	
X	X	L	L	X	L	NC	a LOW-level on \overline{MR} only affects the shift registers
X	↑	L	L	X	L	L	empty shift register loaded into storage register
X	X	H	L	X	L	Z	shift register clear; parallel outputs in high-impedance OFF-state
↑	X	L	H	H	Q6S	NC	logic HIGH-level shifted into shift register stage 0. Contents of all shift register stages shifted through, e.g. previous state of stage 6 (internal Q6S) appears on the serial output (Q7S).
X	↑	L	H	X	NC	QnS	contents of shift register stages (internal QnS) are transferred to the storage register and parallel output stages
↑	↑	L	H	X	Q6S	QnS	contents of shift register shifted through; previous contents of the shift register is transferred to the storage register and the parallel output stages

- [1] H = HIGH voltage state;
 L = LOW voltage state;
 ↑ = LOW-to-HIGH transition;
 X = don't care;
 NC = no change;
 Z = high-impedance OFF-state.

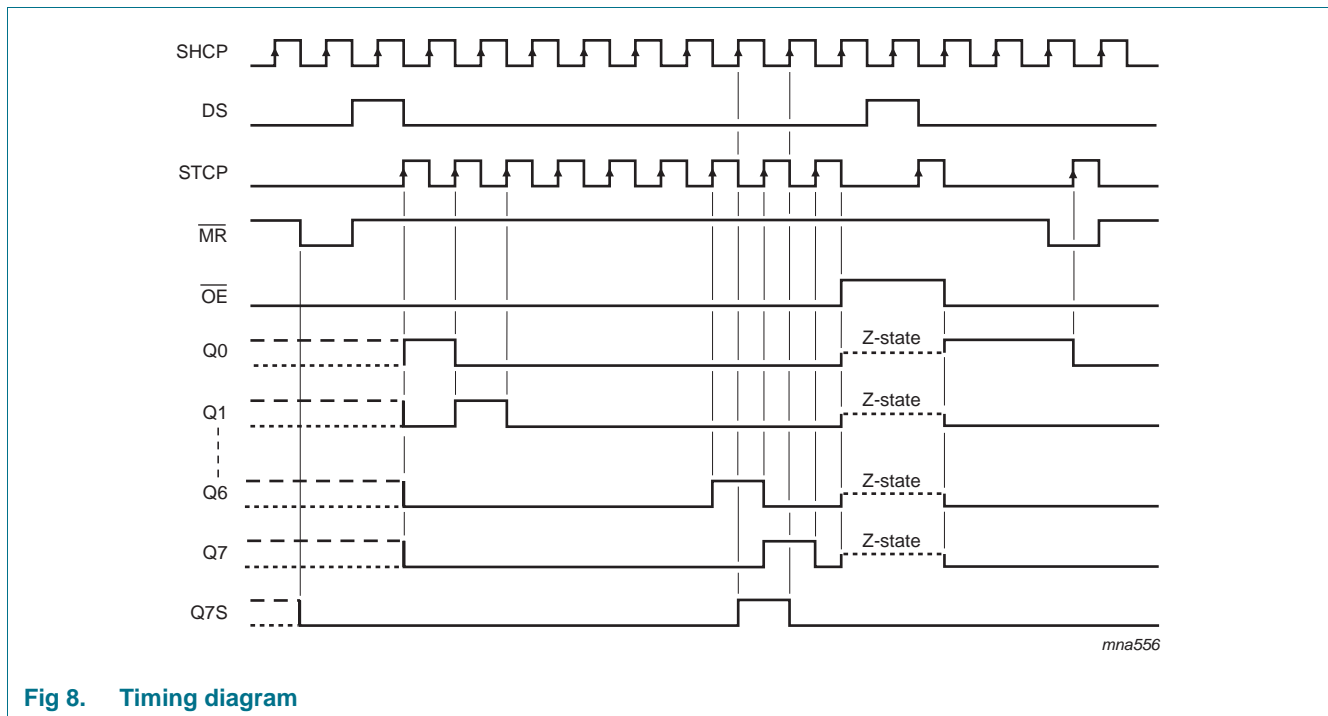


Fig 8. Timing diagram

8. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134). Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{CC}	supply voltage		-0.5	+7	V
I_{IK}	input clamping current	$V_I < -0.5\text{ V}$ or $V_I > V_{CC} + 0.5\text{ V}$	-	± 20	mA
I_{OK}	output clamping current	$V_O < -0.5\text{ V}$ or $V_O > V_{CC} + 0.5\text{ V}$	-	± 20	mA
I_O	output current	$V_O = -0.5\text{ V}$ to $(V_{CC} + 0.5\text{ V})$			
		pin Q7S	-	± 25	mA
		pins Qn	-	± 35	mA
I_{CC}	supply current		-	70	mA
I_{GND}	ground current		-70	-	mA
T_{stg}	storage temperature		-65	+150	°C
P_{tot}	total power dissipation				
	SO16 package		[1] -	500	mW
	TSSOP16 package		[2] -	500	mW
	DHVQFN16 package		[3] -	500	mW

[1] For SO16 package: P_{tot} derates linearly with 8 mW/K above 70 °C.

[2] For TSSOP16 package: P_{tot} derates linearly with 5.5 mW/K above 60 °C.

[3] For DHVQFN16 package: P_{tot} derates linearly with 4.5 mW/K above 60 °C.

9. Recommended operating conditions

Table 5. Recommended operating conditions

Symbol	Parameter	Conditions	74HC595-Q100			74HCT595-Q100			Unit
			Min	Typ	Max	Min	Typ	Max	
V_{CC}	supply voltage		2.0	5.0	6.0	4.5	5.0	5.5	V
V_I	input voltage		0	-	V_{CC}	0	-	V_{CC}	V
V_O	output voltage		0	-	V_{CC}	0	-	V_{CC}	V
$\Delta t/\Delta V$	input transition rise and fall rate	$V_{CC} = 2.0\text{ V}$	-	-	625	-	-	-	ns/V
		$V_{CC} = 4.5\text{ V}$	-	1.67	139	-	1.67	139	ns/V
		$V_{CC} = 6.0\text{ V}$	-	-	83	-	-	-	ns/V
T_{amb}	ambient temperature		-40	+25	+125	-40	+25	+125	°C

10. Static characteristics

Table 6. Static characteristics

At recommended operating conditions; voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	-40 °C to +85 °C			-40 °C to +125 °C		Unit
			Min	Typ	Max	Min	Max	
74HC595-Q100								
V _{IH}	HIGH-level input voltage	V _{CC} = 2.0 V	1.5	1.2	-	1.5	-	V
		V _{CC} = 4.5 V	3.15	2.4	-	3.15	-	V
		V _{CC} = 6.0 V	4.2	3.2	-	4.2	-	V
V _{IL}	LOW-level input voltage	V _{CC} = 2.0 V	-	0.8	0.5	-	0.5	V
		V _{CC} = 4.5 V	-	2.1	1.35	-	1.35	V
		V _{CC} = 6.0 V	-	2.8	1.8	-	1.8	V
V _{OH}	HIGH-level output voltage	V _I = V _{IH} or V _{IL} all outputs						
		I _O = -20 μA; V _{CC} = 2.0 V	1.9	2.0	-	1.9	-	V
		I _O = -20 μA; V _{CC} = 4.5 V	4.4	4.5	-	4.4	-	V
		I _O = -20 μA; V _{CC} = 6.0 V	5.9	6.0	-	5.9	-	V
		Q7S output						
		I _O = -4 mA; V _{CC} = 4.5 V	3.84	4.32	-	3.7	-	V
		I _O = -5.2 mA; V _{CC} = 6.0 V	5.34	5.81	-	5.2	-	V
		Qn bus driver outputs						
		I _O = -6 mA; V _{CC} = 4.5 V	3.84	4.32	-	3.7	-	V
		I _O = -7.8 mA; V _{CC} = 6.0 V	5.34	5.81	-	5.2	-	V
V _{OL}	LOW-level output voltage	V _I = V _{IH} or V _{IL} all outputs						
		I _O = 20 μA; V _{CC} = 2.0 V	-	0	0.1	-	0.1	V
		I _O = 20 μA; V _{CC} = 4.5 V	-	0	0.1	-	0.1	V
		I _O = 20 μA; V _{CC} = 6.0 V	-	0	0.1	-	0.1	V
		Q7S output						
		I _O = 4 mA; V _{CC} = 4.5 V	-	0.15	0.33	-	0.4	V
		I _O = 5.2 mA; V _{CC} = 6.0 V	-	0.16	0.33	-	0.4	V
		Qn bus driver outputs						
		I _O = 6 mA; V _{CC} = 4.5 V	-	0.15	0.33	-	0.4	V
		I _O = 7.8 mA; V _{CC} = 6.0 V	-	0.16	0.33	-	0.4	V
I _I	input leakage current	V _I = V _{CC} or GND; V _{CC} = 6.0 V	-	-	±1.0	-	±1.0	μA
I _{OZ}	OFF-state output current	V _I = V _{IH} or V _{IL} ; V _{CC} = 6.0 V; V _O = V _{CC} or GND	-	-	±5.0	-	±10	μA
I _{CC}	supply current	V _I = V _{CC} or GND; I _O = 0 A; V _{CC} = 6.0 V	-	-	80	-	160	μA
C _I	input capacitance		-	3.5	-	-	-	pF

Table 6. Static characteristics ...continued

At recommended operating conditions; voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	-40 °C to +85 °C			-40 °C to +125 °C		Unit
			Min	Typ	Max	Min	Max	
74HCT595-Q100								
V _{IH}	HIGH-level input voltage	V _{CC} = 4.5 V to 5.5 V	2.0	1.6	-	2.0	-	V
V _{IL}	LOW-level input voltage	V _{CC} = 4.5 V to 5.5 V	-	1.2	0.8	-	0.8	V
V _{OH}	HIGH-level output voltage	V _I = V _{IH} or V _{IL} ; V _{CC} = 4.5 V						
		all outputs						
		I _O = -20 μA	4.4	4.5	-	4.4	-	V
		Q7S output						
V _{OL}	LOW-level output voltage	V _I = V _{IH} or V _{IL} ; V _{CC} = 4.5 V						
		all outputs						
		I _O = 20 μA	-	0	0.1	-	0.1	V
		Q7S output						
I _I	input leakage current	V _I = V _{CC} or GND; V _{CC} = 5.5 V	-	-	±1.0	-	±1.0	μA
		I _O = -4 mA	3.84	4.32	-	3.7	-	V
		Qn bus driver outputs						
		I _O = -6 mA	3.7	4.32	-	3.7	-	V
I _{OZ}	OFF-state output current	V _I = V _{IH} or V _{IL} ; V _{CC} = 5.5 V;						
		V _O = V _{CC} or GND	-	-	±5.0	-	±10	μA
		I _O = 4.0 mA	-	0.15	0.33	-	0.4	V
		Qn bus driver outputs						
I _{CC}	supply current	V _I = V _{CC} or GND; I _O = 0 A;	-	-	80	-	160	μA
		V _{CC} = 5.5 V						
		per input pin; I _O = 0 A; V _I = V _{CC} - 2.1 V; other inputs at V _{CC} or GND; V _{CC} = 4.5 V to 5.5 V						
ΔI _{CC}	additional supply current	pins $\overline{\text{MR}}$, SHCP, STCP, $\overline{\text{OE}}$	-	150	675	-	735	μA
		pin DS	-	25	113	-	123	μA
C _I	input capacitance		-	3.5	-	-	-	pF

11. Dynamic characteristics

Table 7. Dynamic characteristics

Voltages are referenced to GND (ground = 0 V); for test circuit see [Figure 14](#).

Symbol	Parameter	Conditions	25 °C			-40 °C to +85 °C		-40 °C to +125 °C		Unit
			Min	Typ ^[1]	Max	Min	Max	Min	Max	
74HC595-Q100										
t _{pd}	propagation delay	SHCP to Q7S; see Figure 9 ^[2]								
		V _{CC} = 2 V	-	52	160	-	200	-	240	ns
		V _{CC} = 4.5 V	-	19	32	-	40	-	48	ns
		V _{CC} = 6 V	-	15	27	-	34	-	41	ns
		STCP to Qn; see Figure 10 ^[2]								
		V _{CC} = 2 V	-	55	175	-	220	-	265	ns
		V _{CC} = 4.5 V	-	20	35	-	44	-	53	ns
		V _{CC} = 6 V	-	16	30	-	37	-	45	ns
		MR to Q7S; see Figure 12 ^[3]								
V _{CC} = 2 V	-	47	175	-	220	-	265	ns		
V _{CC} = 4.5 V	-	17	35	-	44	-	53	ns		
V _{CC} = 6 V	-	14	30	-	37	-	45	ns		
t _{en}	enable time	$\overline{\text{OE}}$ to Qn; see Figure 13 ^[4]								
		V _{CC} = 2 V	-	47	150	-	190	-	225	ns
		V _{CC} = 4.5 V	-	17	30	-	38	-	45	ns
		V _{CC} = 6 V	-	14	26	-	33	-	38	ns
t _{dis}	disable time	$\overline{\text{OE}}$ to Qn; see Figure 13 ^[5]								
		V _{CC} = 2 V	-	41	150	-	190	-	225	ns
		V _{CC} = 4.5 V	-	15	30	-	38	-	45	ns
		V _{CC} = 6 V	-	12	27	-	33	-	38	ns
t _w	pulse width	SHCP HIGH or LOW; see Figure 9								
		V _{CC} = 2 V	75	17	-	95	-	110	-	ns
		V _{CC} = 4.5 V	15	6	-	19	-	22	-	ns
		V _{CC} = 6 V	13	5	-	16	-	19	-	ns
		STCP HIGH or LOW; see Figure 10								
		V _{CC} = 2 V	75	11	-	95	-	110	-	ns
		V _{CC} = 4.5 V	15	4	-	19	-	22	-	ns
		V _{CC} = 6 V	13	3	-	16	-	19	-	ns
		MR LOW; see Figure 12								
		V _{CC} = 2 V	75	17	-	95	-	110	-	ns
		V _{CC} = 4.5 V	15	6	-	19	-	22	-	ns
		V _{CC} = 6 V	13	5	-	16	-	19	-	ns

Table 7. Dynamic characteristics ...continuedVoltages are referenced to GND (ground = 0 V); for test circuit see [Figure 14](#).

Symbol	Parameter	Conditions	25 °C			-40 °C to +85 °C		-40 °C to +125 °C		Unit	
			Min	Typ ^[1]	Max	Min	Max	Min	Max		
t _{su}	set-up time	DS to SHCP; see Figure 10									
		V _{CC} = 2 V	50	11	-	65	-	75	-	ns	
		V _{CC} = 4.5 V	10	4	-	13	-	15	-	ns	
		V _{CC} = 6 V	9	3	-	11	-	13	-	ns	
		SHCP to STCP; see Figure 11									
		V _{CC} = 2 V	75	22	-	95	-	110	-	ns	
t _h	hold time	DS to SHCP; see Figure 11									
		V _{CC} = 2 V	3	-6	-	3	-	3	-	ns	
		V _{CC} = 4.5 V	3	-2	-	3	-	3	-	ns	
t _{rec}	recovery time	MR to SHCP; see Figure 12									
		V _{CC} = 2 V	50	-19	-	65	-	75	-	ns	
		V _{CC} = 4.5 V	10	-7	-	13	-	15	-	ns	
f _{max}	maximum frequency	SHCP or STCP; see Figure 9 and Figure 10									
		V _{CC} = 2 V	9	30	-	4.8	-	4	-	MHz	
		V _{CC} = 4.5 V	30	91	-	24	-	20	-	MHz	
C _{PD}	power dissipation capacitance	f _i = 1 MHz; V _I = GND to V _{CC} [6][7]	-	115	-	-	-	-	-	pF	

74HCT595-Q100; V_{CC} = 4.5 V to 5.5 V

t _{pd}	propagation delay	SHCP to Q7S; see Figure 9 [2]	-	25	42	-	53	-	63	ns
		STCP to Qn; see Figure 10 [2]	-	24	40	-	50	-	60	ns
		MR to Q7S; see Figure 12 [3]	-	23	40	-	50	-	60	ns
t _{en}	enable time	OE to Qn; see Figure 13 [4]	-	21	35	-	44	-	53	ns
t _{dis}	disable time	OE to Qn; see Figure 13 [5]	-	18	30	-	38	-	45	ns
t _w	pulse width	SHCP HIGH or LOW; see Figure 9	16	6	-	20	-	24	-	ns
		STCP HIGH or LOW; see Figure 10	16	5	-	20	-	24	-	ns
		MR LOW; see Figure 12	20	8	-	25	-	30	-	ns
t _{su}	set-up time	DS to SHCP; see Figure 10	16	5	-	20	-	24	-	ns
		SHCP to STCP; see Figure 11	16	8	-	20	-	24	-	ns
t _h	hold time	DS to SHCP; see Figure 11	3	-2	-	3	-	3	-	ns

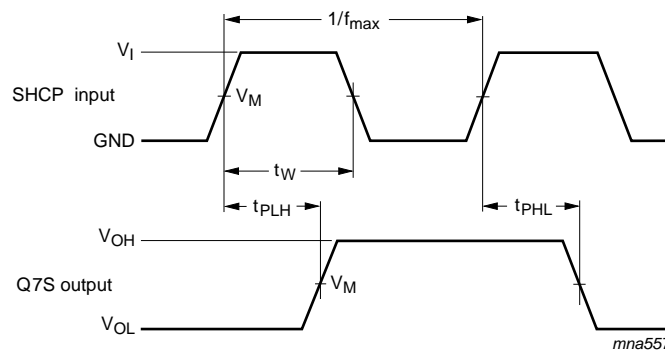
Table 7. Dynamic characteristics ...continued

Voltages are referenced to GND (ground = 0 V); for test circuit see [Figure 14](#).

Symbol	Parameter	Conditions	25 °C			-40 °C to +85 °C		-40 °C to +125 °C		Unit
			Min	Typ ^[1]	Max	Min	Max	Min	Max	
t _{rec}	recovery time	MR to SHCP; see Figure 12	10	-7	-	13	-	15	-	ns
f _{max}	maximum frequency	SHCP and STCP; see Figure 9 and Figure 10	30	52	-	24	-	20	-	MHz
C _{PD}	power dissipation capacitance	f _i = 1 MHz; V _I = GND to V _{CC} [6][7]	-	130	-	-	-	-	-	pF

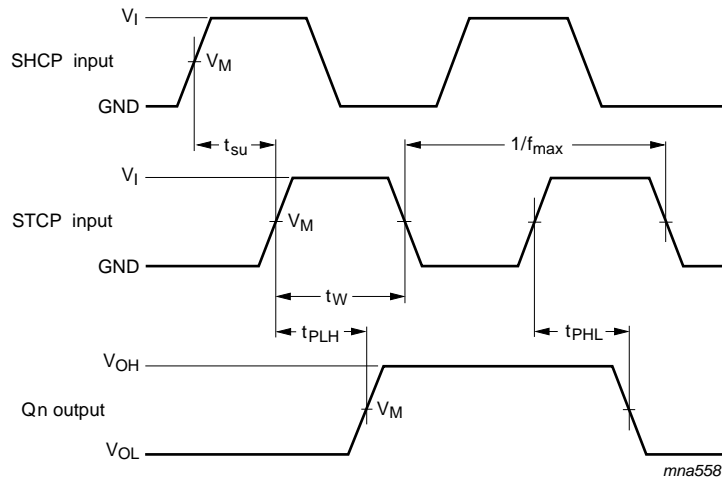
- [1] Typical values are measured at nominal supply voltage.
- [2] t_{pd} is the same as t_{PHL} and t_{PLH}.
- [3] t_{pd} is the same as t_{PHL} only.
- [4] t_{en} is the same as t_{PZL} and t_{PZH}.
- [5] t_{dis} is the same as t_{PLZ} and t_{PHZ}.
- [6] C_{PD} is used to determine the dynamic power dissipation (P_D in μW).
 $P_D = C_{PD} \times V_{CC}^2 \times f_i + \Sigma(C_L \times V_{CC}^2 \times f_o)$ where:
 f_i = input frequency in MHz;
 f_o = output frequency in MHz;
 Σ(C_L × V_{CC}² × f_o) = sum of outputs;
 C_L = output load capacitance in pF;
 V_{CC} = supply voltage in V.
- [7] All 9 outputs switching.

12. Waveforms



Measurement points are given in [Table 8](#).
 V_{OL} and V_{OH} are typical output voltage levels that occur with the output load.

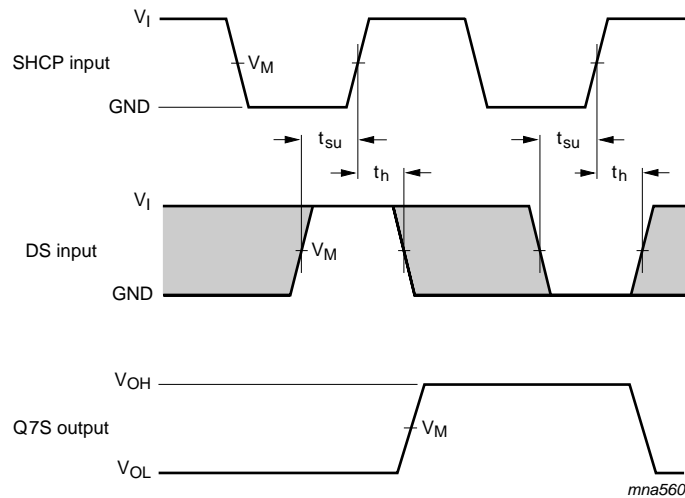
Fig 9. Shift clock pulse, maximum frequency and input to output propagation delays



Measurement points are given in [Table 8](#).

V_{OL} and V_{OH} are typical output voltage levels that occur with the output load.

Fig 10. Storage clock to output propagation delays

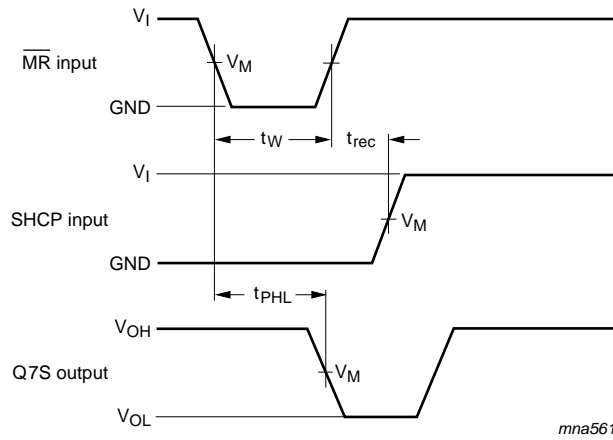


Measurement points are given in [Table 8](#).

The shaded areas indicate when the input is permitted to change for predictable output performance.

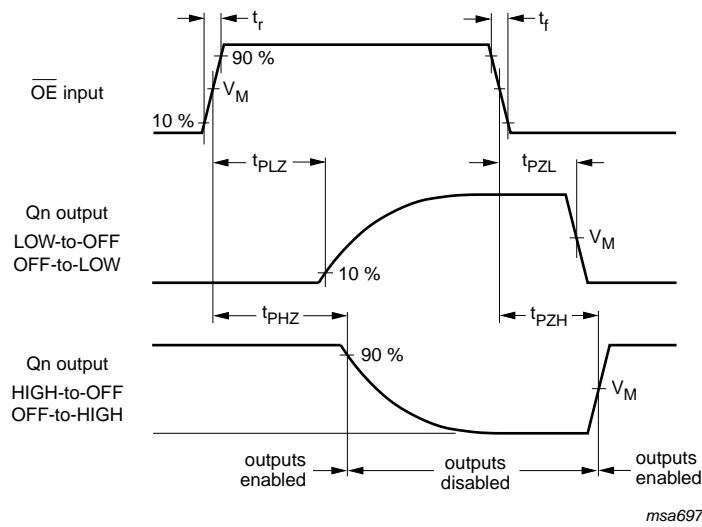
V_{OL} and V_{OH} are typical output voltage levels that occur with the output load.

Fig 11. Data set-up and hold times



Measurement points are given in [Table 8](#).
 V_{OL} and V_{OH} are typical output voltage levels that occur with the output load.

Fig 12. Master reset to output propagation delays

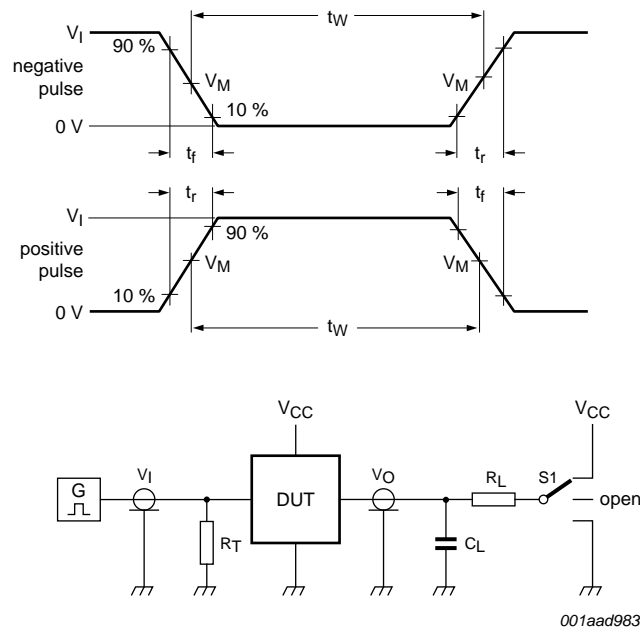


Measurement points are given in [Table 8](#).
 V_{OL} and V_{OH} are typical output voltage levels that occur with the output load.

Fig 13. Enable and disable times

Table 8. Measurement points

Type	Input	Output
	V_M	V_M
74HC595-Q100	$0.5V_{CC}$	$0.5V_{CC}$
74HCT595-Q100	1.3 V	1.3 V



Test data is given in [Table 9](#).

Definitions for test circuit:

C_L = load capacitance including jig and probe capacitance.

R_L = load resistance.

R_T = termination resistance should be equal to the output impedance Z_o of the pulse generator.

S1 = test selection switch.

Fig 14. Test circuit for measuring switching times

Table 9. Test data

Type	Input		Load		S1 position		
	V_I	t_r, t_f	C_L	R_L	t_{PHL}, t_{PLH}	t_{PZH}, t_{PHZ}	t_{PZL}, t_{PLZ}
74HC595-Q100	V_{CC}	6 ns	50 pF	1 k Ω	open	GND	V_{CC}
74HCT595-Q100	3 V	6 ns	50 pF	1 k Ω	open	GND	V_{CC}

13. Package outline

SO16: plastic small outline package; 16 leads; body width 3.9 mm

SOT109-1

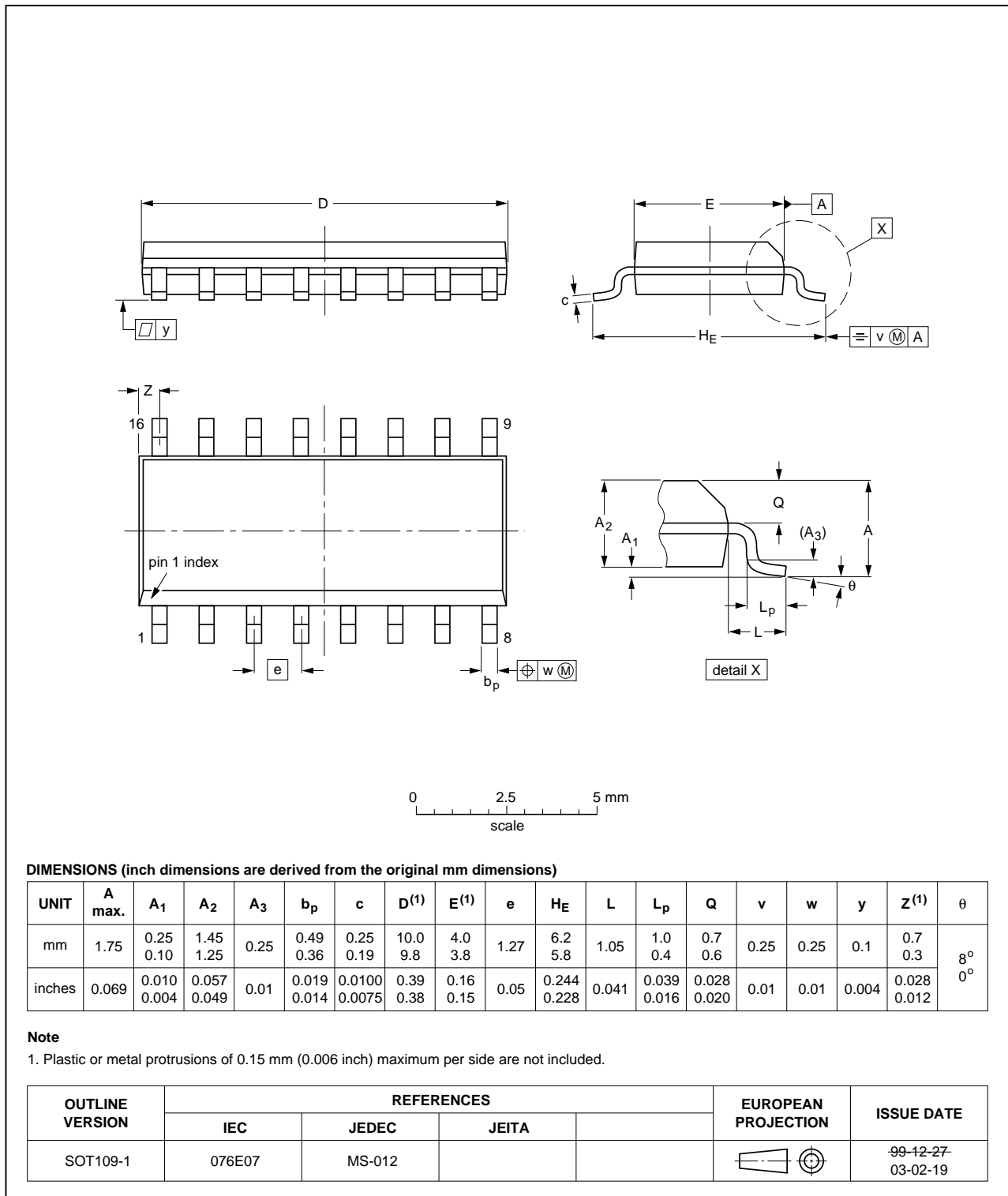


Fig 15. Package outline SOT109-1 (SO16)

TSSOP16: plastic thin shrink small outline package; 16 leads; body width 4.4 mm

SOT403-1

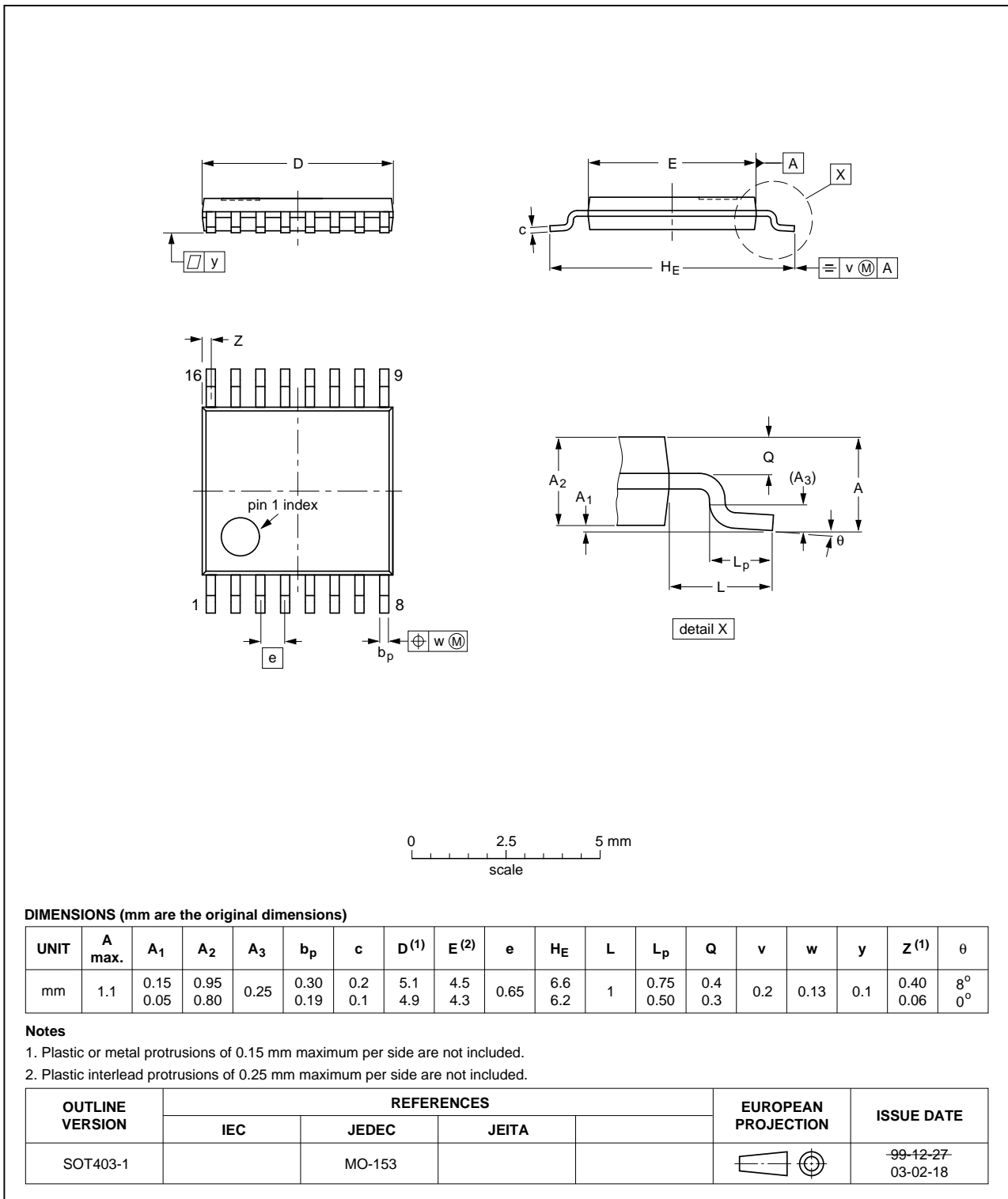


Fig 16. Package outline SOT403-1 (TSSOP16)

DHVQFN16: plastic dual in-line compatible thermal enhanced very thin quad flat package; no leads; 16 terminals; body 2.5 x 3.5 x 0.85 mm

SOT763-1

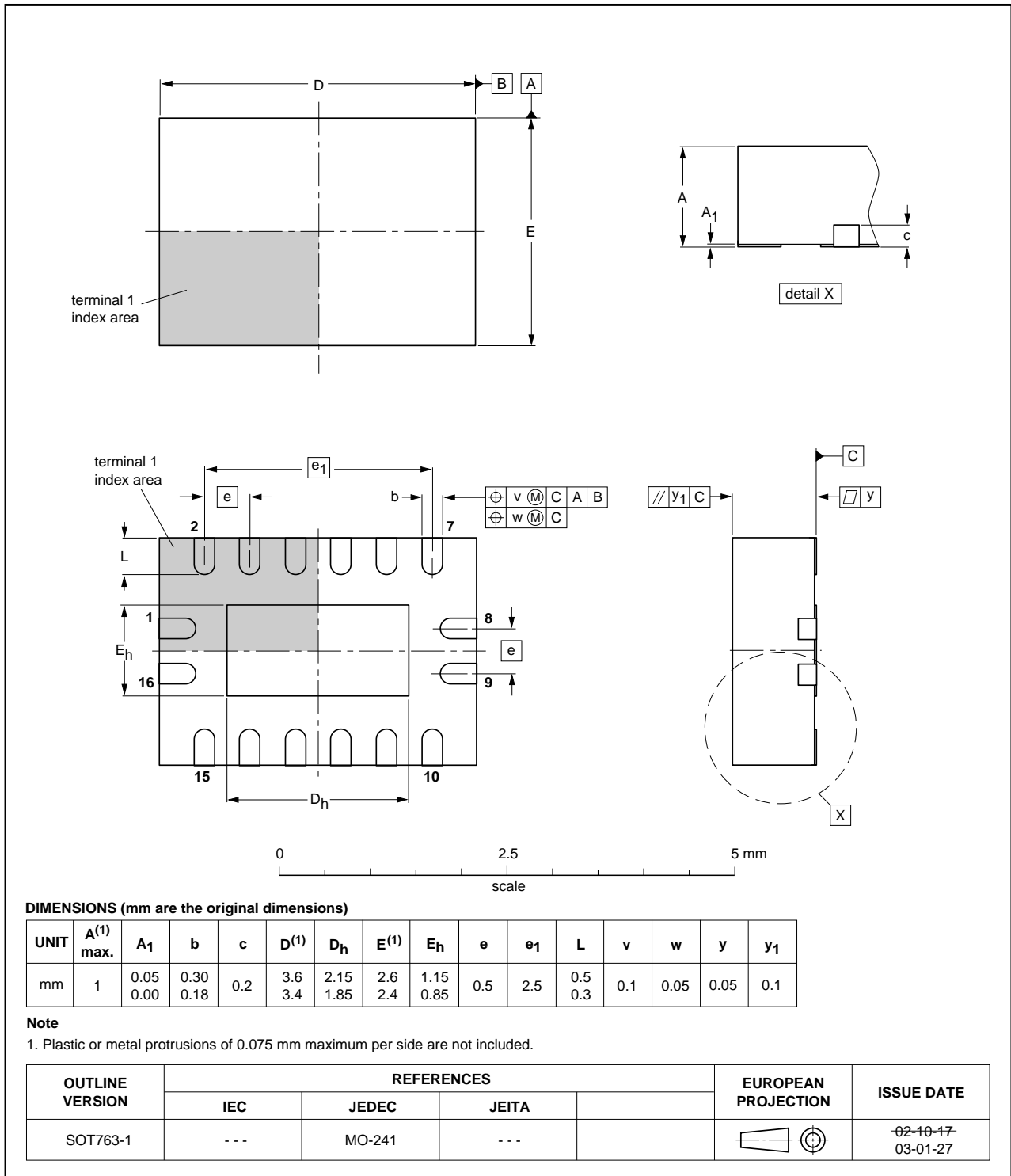


Fig 17. Package outline SOT763-1 (DHVQFN16)

14. Abbreviations

Table 10. Abbreviations

Acronym	Abbreviation
CMOS	Complementary Metal Oxide Semiconductor
DUT	Device Under Test
ESD	ElectroStatic Discharge
HBM	Human Body Model
LSTTL	Low-power Schottky Transistor-Transistor Logic
MM	Machine Model
MIL	Military

15. Revision history

Table 11. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
74HC_HCT595_Q100 v.1	20120802	Product data sheet	-	-

16. Legal information

16.1 Data sheet status

Document status ^{[1][2]}	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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[2] The term 'short data sheet' is explained in section "Definitions".

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